

IFW

Docket Number: 044182-0308723

PATENT APPLICATION



Client Reference:

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re the Application of

RAYMOND H. KRAFT

Group Art Unit: 2621

Application No.: 10/800,420

Examiner:

Filed: March 12, 2004

Confirmation No.: 8417

For: SYSTEM AND METHOD OF NON-LINEAR GRID FITTING AND COORDINATE
SYSTEM MAPPING

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

The citations listed on the enclosed PTO Form-1449 are submitted herewith in accordance with 37 C.F.R. §§1.97 and 1.98, and in compliance with Applicants' duty of disclosure as set forth in 37 C.F.R. §1.56. The documents were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Applicants request that the Examiner fully consider the submitted documents during prosecution of the present application, and that the documents be made of record therein and be listed in the "References Cited" section on the face of any patent to issue therefrom. Additionally, Applicants request return of a copy of the enclosed PTO Form-1449 with the Examiner's initials in the left column per M.P.E.P. 609 III C(2).

This Information Disclosure Statement is not to be construed as a representation that the listed citations satisfy the requirements to be considered prior art under any of the various subsections of 35 U.S.C. §§102 and 103, nor that any one of the listed citations establishes,

either individually or in combination with other information, a *prima facie* case of unpatentability of any claim in the above-identified patent application.

Additionally, this Information Disclosure Statement is not to be construed as a representation that a thorough search of the art has been conducted by Applicants, nor that additional information unknown to Applicants and relevant to the examination of this patent application does not exist.

Applicants believe that this Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits in the present application; accordingly, neither certification nor fee is required pursuant to 37 C.F.R §1.97. However, the Commissioner is hereby authorized to charge any fee required to deposit account 50-2212 under Order No. 044182-0308723.

Respectfully Submitted,



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Date: October 13, 2004
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CERTIFICATION UNDER 37 C.F.R. §§ 1.8 and/or 1.10*

(When using Express Mail, the Express Mail label number is *mandatory*; *Express Mail certification is optional*.)

I hereby certify that, on the date shown below, this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.



Signature

Date: October 13, 2004

KIM A. CABELLO

(type or print name of person certifying)

* Only the date of filing (§ 1.6) will be the date used in a patent term adjustment calculation, although the date on any certificate of mailing or transmission under § 1.8 continues to be taken into account in determining timeliness. See § 1.703(f). Consider "Express Mail Post Office to Addressee" (§ 1.10) or facsimile transmission (§ 1.6(d)) for the reply to be accorded the earliest possible filing date for patent term adjustment calculations.

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office



Atty. Dkt. No.	M#	Client Ref.
	044182	308723

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Kraft, Raymond H.

Appln. No.: 10/800,420

Filing Date: March 12, 2004

Date: October 13, 2004

Page 1 of 1

Examiner:

Group Art Unit: 2621

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR	4,467,211	08/1984	Smith	250	492.2	05/23/83
	BR	6,178,272	01/2001	Segman	382	298	02/02/99
	CR						
	DR						
	ER						
	FR						

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
	GR								
	HR								
	IR								
	JR								

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

	KR	QI, Fei; Chengying Hua, "Efficient automated microarray image analysis" Second International Conference on Image and Graphics, SPIE Vol. 4875 (2002) pp. 567-574						
	LR	SCHATTENBURG, M. L., C. Chen, P. N. Everett, J. Ferrera, P. Konkola, and H. I. Smith, "Sub-100 nm metrology using interferometrically produced fiducials" J. VAc. Sci. Technol. B 17(6), Nov/Dec 1999, pp. 2692-2697						
	MR	BRANDLE, Norbert, H. Lapp, and H. Bischof, "Automatic Grid Fitting for Genetic Spot Array Images Containing Guide Spots" Lecture Notes in Computer Science, Springer Verlag, New York, NY, US, Vol. 1689, September 1999 pp. 357-366						
	NR							
	OR							
	PR							

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.